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## Beräkning av osäkerhet hos vågformsparametrar

*Computation of waveform parameter uncertainties*

Som svensk standard gäller europastandarden EN 62754:2017. Den svenska standarden innehåller den officiella engelska språkversionen av EN 62754:2017.

### Nationellt förord

Europastandarden EN 62754:2017

består av:

- **europastandardens ikraftsättningsdokument**, utarbetat inom CENELEC
- **IEC 62754, First edition, 2017 - Computation of waveform parameter uncertainties**

utarbetad inom International Electrotechnical Commission, IEC.

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ICS 17.220.20

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EUROPEAN STANDARD

**EN 62754**

NORME EUROPÉENNE

EUROPÄISCHE NORM

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English Version

## Computation of waveform Parameter uncertainties (IEC 62754:2017)

Calcul des incertitudes des paramètres des formes d'onde  
(IEC 62754:2017)

Berechnung der Messunsicherheiten von  
Schwingungsabbildparametern  
(IEC 62754:2017)

This European Standard was approved by CENELEC on 2017-06-28. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels**

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## **European foreword**

The text of document 85/585/FDIS, future edition 1 of IEC 62754, prepared by IEC/TC 85 "Measuring equipment for electrical and electromagnetic quantities" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62754:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-03-28
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-06-28

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## **Endorsement notice**

The text of the International Standard IEC 62754:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated :

IEC 60359:2001

NOTE

Harmonized as EN 60359:2002.

-  
**Annex ZA**  
 (normative)

**Normative references to international publications  
 with their corresponding European publications**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cenelec.eu](http://www.cenelec.eu).

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60469	2013	Transitions, pulses and related waveforms - Terms, definitions and algorithms	EN 60469	2013

## CONTENTS

FOREWORD.....	4
1 Scope.....	6
2 Normative references .....	6
3 Terms and definitions .....	6
4 Waveform measurement.....	16
4.1 General.....	16
4.2 Waveform parameters.....	17
4.3 Waveform measurement process .....	17
4.3.1 General .....	17
4.3.2 General description of the measurement system.....	18
5 Waveform and waveform parameter corrections .....	19
5.1 General.....	19
5.2 Waveform parameter corrections .....	19
5.3 Waveform corrections and waveform reconstruction.....	20
5.3.1 General .....	20
5.3.2 Sample-by-sample correction .....	20
5.3.3 Entire waveform correction .....	20
6 Uncertainties .....	22
6.1 General.....	22
6.2 Propagation of uncertainties .....	22
6.2.1 General .....	22
6.2.2 Uncorrelated input quantities .....	23
6.2.3 Correlated input quantities.....	23
6.3 Pooled data and its standard deviation.....	23
6.4 Expanded uncertainty and coverage factor.....	25
6.4.1 General .....	25
6.4.2 Effective degrees of freedom .....	27
6.5 Entire waveform uncertainties .....	28
7 Waveform parameter uncertainties .....	29
7.1 General.....	29
7.2 Amplitude parameters .....	30
7.2.1 State levels.....	30
7.2.2 State boundaries .....	35
7.2.3 Waveform amplitude (state levels) .....	36
7.2.4 Impulse amplitude (state levels) .....	37
7.2.5 Percent reference levels (state levels, waveform amplitude) .....	37
7.2.6 Transition settling error (state levels, waveform amplitude).....	38
7.2.7 Overshoot aberration (state levels, waveform amplitude).....	38
7.2.8 Undershoot aberration (state levels, waveform amplitude) .....	39
7.3 Temporal parameters.....	39
7.3.1 Initial instant.....	39
7.3.2 Waveform epoch.....	40
7.3.3 Reference level instants (percent reference levels, waveform epoch, initial instant).....	41
7.3.4 Impulse centre instant (impulse amplitude, reference level instants) .....	42
7.3.5 Transition duration (reference level instants) .....	42

7.3.6	Transition settling duration (reference level instants) .....	43
7.3.7	Pulse duration (reference level instants) .....	43
7.3.8	Pulse separation (reference level instants) .....	43
7.3.9	Waveform delay (advance) (reference level instants) .....	44
8	Monte Carlo method for waveform parameter uncertainty estimates .....	44
8.1	General guidance and considerations .....	44
8.2	Example: state level.....	44
Annex A (informative) Demonstration example for the calculation of the uncertainty of state levels using the histogram mode according to 7.2.1.2.....		46
A.1	Waveform measurement .....	46
A.2	Splitting the bimodal histogram and determining the state levels.....	46
A.3	Uncertainty of state levels.....	47
Annex B (informative) Computation of $\Sigma_L$ and $\Sigma_Y$ for estimating the uncertainty of state levels using the shorth method according to 7.2.1.3 .....		49
Bibliography.....		52
Figure 1 – Reference levels, reference level instants, waveform amplitude, and transition duration for a single positive-going transition.....		7
Figure 2 – Overshoot, undershoot, state levels, and state boundaries for a single positive-going transition .....		11
Figure 3 – Creation of measured, corrected, and reconstructed waveforms and the final estimate of the input signal.....		17
Figure 4 – Example of waveform bounds focusing on the trajectories that impact pulse parameter measurements .....		28
Figure 5 – Relationship between selected waveform parameters .....		30
Figure A.1 – Waveform obtained from the measurement of a step-like signal from which the state levels and uncertainties are calculated .....		46
Figure A.2 – Histograms of state s1 (a) and state s2 (b) of the step-like waveform plotted in Figure A.1 .....		47
Figure B.1 – Diagram showing location of waveform elements, $y_{(\beta)}^{(\alpha)}$ , in $Y_1$ and $Y_2$ , and the construction of $Y$ from $Y_1$ and $Y_2$ .....		49
Table 1 – Value of the coverage factor $k_p$ that encompasses the fraction $p$ of the $t$ - distribution for different degrees of freedom (from ISO/IEC Guide 98-3).....		26
Table 2 – Different methods for determining state levels, as given in IEC 60469, and their uncertainty type and method of computation .....		31
Table 3 – Different methods for determining state boundaries and their uncertainty type and method of computation.....		36
Table 4 – Variables contributing to the uncertainty in overshoot.....		39
Table 5 – Variables contributing to the uncertainty in the reference level instant.....		42
Table A.1 – Uncertainty contributions and total uncertainty for $level(s_i)$ determined from histogram modes .....		48

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**COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES**

## FOREWORD

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International Standard IEC 62754 has been prepared by IEC technical committee 85: Measuring equipment for electrical and electromagnetic quantities.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
85/585/FDIS	85/X588/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The terms used throughout this document which have been defined in Clause 3 are in italic type.



The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
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## COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES

### 1 Scope

This document specifies methods for the computation of the temporal and amplitude parameters and their associated uncertainty for step-like and impulse-like waveforms. This document is applicable to any and all industries that generate, transmit, detect, receive, measure, and/or analyse these types of pulses.

### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60469:2013, *Transitions, pulses and related waveforms – Terms, definitions and algorithms*